1. GENERAL

1.01 This section is reissued to:

(a) Add Electronic Translation System (ETS) features

(b) To change key selection of circuits and test conditions at the master test frame (MTF) in accordance with Section 218-106-301.

Since this reissue is a general revision, arrows ordinarily used to indicate changes have been omitted. This reissue affects Equipment Test Lists.

1.02 The tests covered are:

A. Operation Test: This test checks: (1) sleeve continuity, (2) polarity of tip and ring (3) connection to and coin refund from the coin supervisory circuit.

B. Trunk-Busy Features: This test checks: (1) the ability of the trunk to test busy (2) the ability to seize trunk when made busy.

1.03 When the office is arranged for ETS, the distributors and scanners associated with the marker and trunk used in the test call must be in service or in a maintenance-busy condition—not in an out-of-service condition. To change a scanner or distributor from an out-of-service to a maintenance-busy condition, use the procedure given in the following section for the office arrangement.


1.04 When the trunk under test is arranged for ETS, the first completed test call from the MTF will cause the TST bit to be set in the trunk register associated with the selected trunk, enabling trunk scanning to be repeated on the FT lamp at the MTF trunk test circuit. As long as the TST bit is set in the trunk register, supervision will continue to be repeated on the lamp, even on service calls. The TST bit will remain set in the trunk register until (1) a test call is made from the MTF to another trunk, or (2) the command STOP:TRK TST is entered at the maintenance TTY.

1.05 On Issue 76D of SD-25800-01, a group of 18 “class of test” lamps was replaced by a single “start test” lamp designated STT. Since the designation given to the lamp is not specific, the lamp will not be called out in the section, as well as the 18 discontinued lamps, such as DT, ORIG, ITDO, ITNP, OGT, etc.

1.06 Lettered Steps: A letter a, b, c, etc, added to a step number in Parts 3 and 4 of this section indicates an action which may or may not be required depending on local conditions. The condition under which a lettered step or a series of lettered steps should be made is given in the ACTION column, and all steps governed by the same condition are designated by the same letter within a test. Where a condition does not apply, all steps designated by that letter should be omitted.

1.07 The manner of selecting some circuits and test conditions at the MTF and its associated circuits varies depending on the apparatus options furnished with these circuits. Therefore, where variable means of selection are provided, precise instructions for the selection of circuits and test conditions are not given. Precise instructions for the use of these variable means are given in Section 218-106-301.

NOTICE
Not for use or disclosure outside the Bell System except under written agreement

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1.08 The location statement, At MTF—, is used to refer to all apparatus located on the four basic bays of the MTF.

2. APPARATUS

3. PREPARATION

Refer to 1.03 through 1.08.

<table>
<thead>
<tr>
<th>STEP</th>
<th>ACTION</th>
<th>VERIFICATION</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>Restore all keys and switches to normal.</td>
<td>All lamps extinguished.</td>
</tr>
<tr>
<td>2</td>
<td>Momentarily operate RL key.</td>
<td></td>
</tr>
<tr>
<td>3</td>
<td>Select coin class of service and rate treatment as required.</td>
<td></td>
</tr>
<tr>
<td>4</td>
<td>Operate FS, TS, SCN, TLK, CN keys.</td>
<td></td>
</tr>
<tr>
<td>5</td>
<td>Select route advance as required.</td>
<td></td>
</tr>
<tr>
<td>6</td>
<td>Select trunk under test.</td>
<td></td>
</tr>
<tr>
<td>7</td>
<td>Select MISC class of test.</td>
<td></td>
</tr>
<tr>
<td>8</td>
<td>Select marker.</td>
<td></td>
</tr>
<tr>
<td>9</td>
<td>Select originating class of call with associated translator indication.</td>
<td></td>
</tr>
<tr>
<td>10</td>
<td>Operate STK-CN key.</td>
<td></td>
</tr>
<tr>
<td>11a</td>
<td>If ETS provided— Operate PCS, PTS keys.</td>
<td></td>
</tr>
</tbody>
</table>

4. METHOD

A. Operation Test

12 Momentarily operate ST key. AS lamp lighted. PK lamp not lighted. If ETS provided— FT lamp lighted. CR lamp momentarily lighted. CND lamp lighted.

13 Restore TLK key. AS lamp remains lighted. When assistant answers and attempts refund— CR lamp momentarily lighted. If assistant attempts to ring on line— R_ lamp lighted while ringing applied.
### STEP 14
When R lamp lights—
Operate TLK key.
Inform assistant that this is a test call, and request assistant to release circuit.

### STEP 15
Restore STK-CN key.

### STEP 16
Restore TLK key.

### STEP 17
Momentarily operate RL key.

### STEP 18
Restore all keys and switches not required in next test.

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### B. Trunk Busy Feature

#### STEP 12
Momentarily operate ST key.

#### STEP 13
Restore STK-CN key.

#### STEP 14
Restore TLK key.

#### STEP 15
Momentarily operate RL key.

#### STEP 16
At relay rack location of trunk under test—
Operate MB switch to MB position.

#### STEP 17
Momentarily operate ST key.

#### STEP 18
Momentarily operate RL key.

#### STEP 19
Operate NTTS, NTFS keys.

#### STEP 20
Repeat Steps 12 and 13.

#### STEP 21
Restore TLK key.
<table>
<thead>
<tr>
<th>STEP</th>
<th>ACTION</th>
<th>VERIFICATION</th>
</tr>
</thead>
</table>
| 22   | Momentarily operate RL key. | All lamps extinguished.  
If ETS provided—  
FT lamp remains lighted. |
| 23   | At relay rack location of trunk under test—  
Restore MB switch to N position. | MB lamp extinguished.  
If ETS provided—  
At MTF—  
FT lamp extinguished. |
| 24   | Restore all keys and switches not required in next test. | |